


<b>Search Notes</b>  	<b>Application/Control No.</b>  10552315	<b>Applicant(s)/Patent Under Reexamination</b>  AKHAPKINA ET AL.
	<b>Examiner</b>  Kim, Jennifer	<b>Art Unit</b>  1617

### SEARCHED

Class	Subclass	Date	Examiner
514	408, 545	3/15/2007	jmk
	Updated	7/30/2007	jmk
	Updated	2/13/2008	jmk

### SEARCH NOTES

Search Notes	Date	Examiner
Registry; inventor search; international search report; chemdraw	3/15/2007	jmk
Updated; STN (registry) see search terms.	7/30/2007	jmk
Updated	2/13/2008	jmk

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner